 rch Note	

	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/723,658	TOGASHI ET AL.	
ľ	Examiner	Art Unit	
	Jason Y. Pahng	3725	

Jason Y. Pahng

	CHED	SEAR	
Examiner	Date	Subclass	Class
5 JYP	7/5/2005	264	241
5 JYP	7/5/2005	268	241

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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DATE 7/5/2005	EXMR
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	JYP